

**SINGAPORE LABORATORY
ACCREDITATION SCHEME**



Schedule

Techsystems Services & Integration Asia Pte Ltd
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Loyang Industrial Estate
Singapore 508913

Certificate No. : LA-2000-0175-C
Issue No. : 25
Date : 29 June 2019
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FIELD OF TESTING : Calibration and Measurement

MEASURED QUANTITIES/INSTRUMENTS/ RANGE TO BE CALIBRATED	METHOD/FREQUENCY	CALIBRATION AND MEASUREMENT CAPABILITY (CMC*)
1 DC Voltage 1.1 Source 0 ~ ± 100 mV ± 0.1 V ~ ± 1 V ± 1 V ~ ± 10 V ± 10 V ~ ± 100 V ± 10 V ~ ± 1000 V	TS-08 Direct measurement with Precision multimeter	17 ppm + 0.35 µV 8 ppm + 0.35 µV 8 ppm + 1 µV 10 ppm + 36 µV 25 ppm + 0.2 mV
1.2 Measurement 1 V 10 V 0 ~ ± 220 mV ± 0.22 V ~ ± 2.2 V ± 2.2 V ~ ± 11 V ± 11 V ~ ± 22 V ± 22 V ~ ± 220 V ± 220 V ~ ± 1000 V	TS-41 Comparison with a calibrated Standard zener diode, Potentiometric Measurement TS-08 Direct measurement of DC Voltage sourced by Multifunction Calibrator	3 µV 7 µV 8 ppm + 0.5 µV 6 ppm + 1 µV 4 ppm + 3 µV 4 ppm + 6 µV 6 ppm + 50 µV 7 ppm + 500 µV

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2. AC Voltage Source	TS-42 Comparison with DC voltage Source through calibrated AD/DC transfer unit	
30 mV	100 Hz	37 ppm
30 mV	500 kHz	181 ppm
0.3 V	100 Hz	13 ppm
3 V	10 Hz	16 ppm
3 V	100 Hz	11 ppm
3 V	500 kHz	19 ppm
30 V	100 Hz	16 ppm
30 V	100 kHz	26 ppm
300 V	20 kHz	15 ppm
300 V	100 kHz	61 ppm
1000 V	45 Hz	18 ppm
1000 V	100 Hz	14 ppm
1000 V	1 kHz	14 ppm
1000 V	5 kHz	27 ppm
1000 V	7 kHz	27 ppm
1 ~ 10 mV	TS-42 Direct measurement with Precision multimeter	(% reading + floor)
	10 Hz ~ 20 Hz	0.47 % + 37 µV
	20 Hz ~ 40 Hz	0.18 % + 29 µV
	40 Hz ~ 100 Hz	0.07 % + 29 µV
	100 Hz ~ 20 kHz	0.03 % + 29 µV
	20 kHz ~ 50 kHz	0.18 % + 29 µV
	50 kHz ~ 100 kHz	0.81 % + 41 µV
	100 kHz ~ 250 kHz	4.7 % + 81 µV
10 mV ~ 100 mV	10 Hz ~ 20 Hz	0.47 % + 0.024 mV
	20 Hz ~ 40 Hz	0.18 % + 0.024 mV
	40 Hz ~ 100 Hz	0.07 % + 0.012 mV
	100 Hz ~ 20 kHz	0.03 % + 0.012 mV
	20 kHz ~ 50 kHz	0.18 % + 0.047 mV
	50 kHz ~ 100 kHz	0.69 % + 0.093 mV
	100 kHz ~ 250 kHz	2.4 % + 0.58 mV
	500 kHz ~ 1 MHz	6 % + 2.4 mV
	1 MHz ~ 2 MHz	12 % + 6 mV



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0.1 V ~ 1 V	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 100 Hz 100 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 250 kHz 250 kHz ~ 500 kHz 500 kHz ~ 1 MHz 1 MHz ~ 2 MHz	0.47 % + 0.25 mV 0.18 % + 0.24 mV 0.07 % + 0.12 mV 0.03 % + 0.12 mV 0.18 % + 0.47 mV 0.69 % + 0.93 mV 2.4 % + 5.8 mV 3.5 % + 7 mV 6 % + 24 mV 12 % + 60 mV
1 V ~ 10 V	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 100 Hz 100 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 250 kHz 250 kHz ~ 500 kHz 500 kHz ~ 1 MHz 1 MHz ~ 2 MHz	0.47 % + 2.4 mV 0.18 % + 2.4 mV 0.07 % + 1.2 mV 0.04 % + 1.2 mV 0.18 % + 4.7 mV 0.69 % + 9.3 mV 2.4 % + 58 mV 3.5 % + 70 mV 6 % + 240 mV 12 % + 600 mV
10 V ~ 100 V	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 100 Hz 100 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 250 kHz 250 kHz ~ 500 kHz 500 kHz ~ 1 MHz	0.47 % + 0.024 V 0.18 % + 0.024 V 0.07 % + 0.012 V 0.04 % + 0.012 V 0.18 % + 0.047 V 0.69 % + 0.093 V 2.4 % + 0.58 V 3.5 % + 0.7 V 6 % + 2.4 V
100 V ~ 1000 V	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 100 Hz 100 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz	0.5 % + 0.35 V 0.2 % + 0.35 V 0.1 % + 0.24 V 0.07 % + 0.24 V 0.18 % + 0.47 V 0.69 % + 2.4 V



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2.2 Measurement	TS-08 Direct measurement of AC Voltage sourced by Multifunction Calibrator	
0.22 mV ~ 2.2 mV	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 300 kHz 300 kHz ~ 500 kHz 500 kHz ~ 1 MHz	0.024 % + 5 µV 0.009 % + 5 µV 0.008 % + 5 µV 0.02 % + 5 µV 0.05 % + 6 µV 0.11 % + 11 µV 0.14 % + 21 µV 0.27 % + 21 µV
2.2 mV ~ 22 mV	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 300 kHz 300 kHz ~ 500 kHz 500 kHz ~ 1 MHz	0.024 % + 5 µV 0.009 % + 5 µV 0.008 % + 5 µV 0.02 % + 5 µV 0.05 % + 6 µV 0.11 % + 11 µV 0.14 % + 21 µV 0.27 % + 21 µV
22 mV ~ 220 mV	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 300 kHz 300 kHz ~ 500 kHz 500 kHz ~ 1 MHz	0.024 % + 13 µV 0.009 % + 8 µV 0.008 % + 8 µV 0.02 % + 8 µV 0.046 % + 18 µV 0.1 % + 21 µV 0.14 % + 26 µV 0.27 % + 46 µV
0.22 V ~ 2.2 V	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 300 kHz 300 kHz ~ 500 kHz 500 kHz ~ 1 MHz	0.024 % + 41 µV 0.009 % + 16 µV 0.0045 % + 9 µV 0.0075 % + 11 µV 0.011 % + 31 µV 0.042 % + 81 µV 0.1 % + 210 µV 0.17 % + 310 µV

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2.2 V ~ 22 V	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz 100 kHz ~ 300 kHz 300 kHz ~ 500 kHz 500 kHz ~ 1 MHz	0.024 % + 0.41 mV 0.009 % + 0.16 mV 0.0045 % + 0.06 mV 0.0075 % + 0.11 mV 0.01 % + 0.21 mV 0.028 % + 0.7 mV 0.1 % + 2.1 mV 0.15 % + 3.3 mV
22 V ~ 220 V	10 Hz ~ 20 Hz 20 Hz ~ 40 Hz 40 Hz ~ 20 kHz 20 kHz ~ 50 kHz 50 kHz ~ 100 kHz	0.024 % + 4.1 mV 0.009 % + 1.6 mV 0.0052 % + 0.7 mV 0.008 % + 1.1 mV 0.015 % + 2.6 mV
250 V ~ 700 V	50 Hz ~ 1 kHz	0.008 % + 20 mV
3. Resistance	TS-36	
3.1 Measurement (specific value)	Measurement of calibrated resistance values from standard resistors	
1 mΩ		0.2 %
10 mΩ		0.02 %
100 mΩ		0.02 %
0.1 Ω		3 μΩ
1 Ω		4 μΩ
10 Ω		0.04 mΩ
100 Ω		0.46 mΩ
1 kΩ		0.002 Ω
10 kΩ		0.03 Ω
100 kΩ		0.26 Ω
1 MΩ		0.014 MΩ
100 MΩ		0.3 MΩ
1 GΩ		0.002 GΩ
10 GΩ		1.0 %
100 GΩ		0.8 %
1 TΩ		2.0 %



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1 Ω	Measurement of calibrated resistance values from multifunction calibrator	0.11 mΩ
1.9 Ω		0.2 mΩ
10 Ω		0.25 mΩ
19 Ω		0.55 mΩ
100 Ω		1.3 mΩ
190 Ω		2.1 mΩ
1 kΩ		0.010 Ω
1.9 kΩ		0.018 Ω
10 kΩ		0.10 Ω
19 kΩ		0.18 Ω
100 kΩ		1.2 Ω
190 kΩ		2.2 Ω
1 MΩ		0.020 kΩ
1.9 MΩ		0.041 kΩ
10 MΩ		0.42 kΩ
19 MΩ		0.0012 MΩ
100 MΩ		0.012 MΩ
3.2 Measurement (variable value)	Measurement of resistance values generated by multifunction calibrator	
0 ~ 11 Ω		47 ppm + 12 mΩ
11 ~ 33 Ω		35 ppm + 18 mΩ
33 ~ 1100 Ω		33 ppm + 30 mΩ
1.1 ~ 11 kΩ		33 ppm + 0.3 Ω
11 ~ 110 kΩ		33 ppm + 2 Ω
110 ~ 1100 kΩ		37 ppm + 20 Ω
1.1 ~ 3.3 MΩ		70 ppm + 0.2 kΩ
3.3 ~ 11 MΩ		0.015 % + 0.3 kΩ
11 ~ 33 MΩ		0.03 % + 3 kΩ
33 ~ 110 MΩ		0.06 % + 3.5 kΩ
110 ~ 330 MΩ		0.35 % + 0.2 MΩ
330 ~ 1000 MΩ		1.75 % + 0.7 MΩ

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3.3	Source (specific value) 0.1 Ω 1 Ω 10 Ω 100 Ω 1 kΩ 10 kΩ 100 kΩ	Transfer of calibrated resistance values from standard resistors	6 ppm + 35 μΩ 6 ppm + 35 μΩ 6 ppm + 44 μΩ 4 ppm + 0.6 mΩ 3 ppm + 0.0016 Ω 3 ppm + 0.026 Ω 3 ppm + 0.26 Ω
3.4	Source (variable value) 0 Ω ~ 10 Ω 10 Ω ~ 100 Ω 100 Ω ~ 1 kΩ 1 kΩ ~ 10 kΩ 10 kΩ ~ 100 kΩ 100 kΩ ~ 1 MΩ 1 MΩ ~ 10 MΩ 10 MΩ ~ 100 MΩ 100 MΩ ~ 1 GΩ	Resistance value measured by Precision DMM	18 ppm + 60 μΩ 14 ppm + 0.6 mΩ 12 ppm + 0.6 mΩ 12 ppm + 7 mΩ 12 ppm + 0.06 Ω 18 ppm + 3 Ω 58 ppm + 0.2 kΩ 0.06 % + 1.2 kΩ 0.67 % + 0.2 MΩ
4.	DC Current		
4.1	Source 0.1 μA ~ 10 μA 10 μA ~ 1 mA 1 mA ~ 1000 mA 1 A ~ 5 A 5 A ~ 50 A	TS-44 Current calibrated using Ohm's Law	8 ppm + 0.02 nA 8 ppm + 0.2 nA 9 ppm + 120 nA 9 ppm + 3 μA 0.12 %
4.2	Measurement 0 ~ ± 220 μA ± 0.22 mA ~ ± 2.2 mA ± 2.2 mA ~ ± 22 mA ± 22 mA ~ ± 220 mA ± 0.22 A ~ ± 1 A ± 1 ~ ± 2.2 A ± 2.2 A ~ ± 11 A ± 11 A ~ ± 20 A	Measurement of current sourced by multifunction calibrator	41 ppm + 6 nA 36 ppm + 8 nA 36 ppm + 0.05 μA 46 ppm + 1 μA 81 ppm + 13 μA 81 ppm + 120 μA 0.06 % + 0.001 A 0.12 % + 0.001 A



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5. AC Current	TS-44	
5.1 Source	Calibration of AC current using precision multimeter	
10 µA ~ 100 µA	10 Hz – 20 Hz 20 Hz – 45 Hz 45 Hz – 100 Hz 100 Hz – 5 kHz	0.47 % + 0.035 µA 0.18 % + 0.035 µA 0.07 % + 0.035 µA 0.07 % + 0.035 µA
0.1 mA ~ 1 mA	10 Hz – 20 Hz 20 Hz – 45 Hz 45 Hz – 100 Hz 100 Hz – 5 kHz 5 kHz – 20 kHz	0.47 % + 0.24 µA 0.18 % + 0.24 µA 0.07 % + 0.24 µA 0.04 % + 0.24 µA 0.07 % + 0.24 µA
1 mA ~ 10 mA	10 Hz – 20 Hz 20 Hz – 45 Hz 45 Hz – 100 Hz 100 Hz – 5 kHz 5 kHz – 20 kHz	0.47 % + 2.4 µA 0.18 % + 2.4 µA 0.07 % + 2.4 µA 0.04 % + 2.4 µA 0.07 % + 2.4 µA
10 mA ~ 100 mA	10 Hz – 20 Hz 20 Hz – 45 Hz 45 Hz – 100 Hz 100 Hz – 5 kHz 5 kHz – 20 kHz	0.47 % + 24 µA 0.18 % + 24 µA 0.07 % + 24 µA 0.04 % + 24 µA 0.07 % + 24 µA
0.1 A ~ 1 A	10 Hz – 20 Hz 20 Hz – 45 Hz 45 Hz – 100 Hz 100 Hz – 5 kHz 5 kHz – 20 kHz	0.47 % + 240 µA 0.19 % + 240 µA 0.1 % + 240 µA 0.12 % + 240 µA 0.35 % + 240 µA
3 ~ 11 A	TS-44 Transfer of calibrated current value 10 Hz ~ 100 Hz 100 Hz ~ 1 kHz 1 kHz ~ 5 kHz	1.2 % + 0.01 A 0.12 % + 0.01 A 3.5 % + 0.01 A



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11 ~ 20 A	10 Hz ~ 100 Hz 11 ~ 20 A 100 Hz ~ 1 kHz 1 kHz ~ 5 kHz	0.14 % + 0.03 A 10 Hz ~ 100 Hz 0.17 % + 0.02 A 3.5 % + 0.02 A
5.2 Measurement	TS-44 Measurement of AC current generated by multifunction calibrator	
10 µA ~ 220 µA	10 Hz - 20 Hz 20 Hz - 40 Hz 40 Hz - 1 kHz 1 kHz - 5 kHz 5 kHz - 10 kHz	250 ppm + 17 nA 160 ppm + 11 nA 120 ppm + 9 nA 280 ppm + 13 nA 0.11 % + 66 nA
0.22 mA ~ 2.2 mA	10 Hz - 20 Hz 20 Hz - 40 Hz 40 Hz - 1 kHz 1 kHz - 5 kHz 5 kHz - 10 kHz	250 ppm + 0.05 µA 160 ppm + 0.04 µA 120 ppm + 0.04 µA 200 ppm + 0.12 µA 0.11 % + 0.66 µA
2.2 mA ~ 22 mA	10 Hz - 20 Hz 20 Hz - 40 Hz 40 Hz - 1 kHz 1 kHz - 5 kHz 5 kHz - 10 kHz	250 ppm + 0.5 µA 160 ppm + 0.4 µA 120 ppm + 0.4 µA 200 ppm + 0.6 µA 0.11 % + 5.1 µA
22 mA ~ 220 mA	10 Hz - 20 Hz 20 Hz - 40 Hz 40 Hz - 1 kHz 1 kHz - 5 kHz 5 kHz - 10 kHz	250 ppm + 5 µA 160 ppm + 4 µA 120 ppm + 3 µA 200 ppm + 4 µA 0.11 % + 11 µA



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0.22 A ~ 2.2 A	20 Hz - 1 kHz 1 kHz - 5 kHz 5 kHz - 10 kHz	260 ppm + 40 µA 450 ppm + 90 µA 0.7 % + 170 µA
3 A ~ 11 A	45 Hz ~ 100 Hz 100 Hz ~ 1 kHz 1 kHz ~ 5 kHz	0.07 % + 0.01 A 0.12 % + 0.01 A 3.5 % + 0.01 A
11 A ~ 20 A	45 Hz ~ 100 Hz 100 Hz ~ 1 kHz 1 kHz ~ 5 kHz	0.14 % + 0.01 A 0.17 % + 0.01 A 3.5 % + 0.01 A
6. Capacitance Measurement		
100 pF	TS-36	0.06 pF
1 nF	Direct measurement at 1 kHz using standard capacitors	0.6 pF
10 nF		3 pF
100 nF		29 pF
1 µF		0.2 nF
0.19 nF ~ 3.3 nF	Direct measurement using Fluke 5520A	0.04 nF
3.3 nF ~ 33 nF		0.23 nF
33 nF ~ 330 nF		1.57 nF
0.33 µF ~ 3.3 µF		0.02 µF
3.3 µF ~ 33 µF		0.24 µF
33 µF ~ 330 µF		2.24 µF
0.33 mF ~ 3.3 mF		0.03 mF
3.3 mF ~ 33 mF		0.34 mF
33 mF ~ 110 mF		1.67 mF

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7. Inductance Measurement 100 µH 1 mH 10 mH 100 mH 1 H 5 H	TS-36 Direct measurement at 1 kHz using standard inductors	0.38 µH 2.01 µH 13 µH 93 µH 0.93 mH 5.4 mH
8. Frequency 10 MHz Timebase Frequency Output 0.1 Hz 1 kHz 1 MHz 100 MHz 225 MHz 1000 MHz – 26.5 GHz	TS-01 Comparison with Frequency Standard	5.8 E-10 1.3 E-02 1.4 E-09 8.7 E-08 8.7 E-06 6.9 E-10 1.2 E-07
9. High Voltage 1 kV to 10 kV	TS-06 Direct Measurement with a calibrated HV meter DC AC 50 Hz	0.6 % + 5 V 1.2 % + 7 V



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10. Oscilloscope a. Vertical Deflection 1 mV to 10 V ** 1 mV to 60 V **	TS-11 DC Voltage output from Scope Calibrator 50 Ω Input 1 MΩ Input	0.9 % + 0.05 mV 1.2 % + 0.03 mV
b. Horizontal Deflection 10 msec (2 ns to 20 ms) 100 msec (50 ms to 5 s)	TS-11 Time Marker output from Scope Calibrator	8.3 ppm 3.4 ppm
c. Vertical Bandwidth (Cut-off Frequency at 3 dB Bandwidth) 50 kHz to 100 MHz 100 MHz to 300 MHz 300 MHz to 500 MHz 500 MHz to 600 MHz	TS-11 Levelled Sine output from Scope Calibrator	4 % 5 % 8 % 9 %
B. TEMPERATURE		
1.1 Thermal Couple Thermometer <u>Type K</u> -200 °C to 1370 °C <u>Type J</u> -210 °C to 1200 °C <u>Type T</u> -270 °C to -200 °C -200 °C to 400 °C <u>Type E</u> -250 °C to 1000 °C	TS-26 Measurement of reference TC emf generated by precision voltage Source through ice point reference device	0.2 °C 0.2 °C 0.3 °C 0.2 °C 0.2 °C



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1.2 TC Thermometer Calibrator <u>Type K</u> -200 °C to 1370 °C <u>Type J</u> -210 °C to 1200 °C <u>Type T</u> -210 °C to -200 °C -200 °C to 400 °C <u>Type E</u> -250 °C to 1000 °C	TS-26 Measurement of emf sourced by Calibrator through external ice point and check against Corresponding reference TC emf	0.2 °C 0.2 °C 0.3 °C 0.2 °C 0.2 °C
1.3 RTD Thermometer -190 °C to 500 °C	TS-26 Measure RTD resistance and convert to temperature based on ITS90	0.06 °C
1.4 RTD Simulator/Calibrator -190 °C to -50 °C -50 °C to 50 °C 50 °C to 190 °C 190 °C to 500 °C	TS-26 Measure RTD simulated temperature based on ITS90 or simulator formula	0.004 °C 0.005 °C 0.007 °C 0.012 °C

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C. MECHANICAL		
1.1 Weighing Scale <i>Up to 6000 grams</i>	TS-102A The calibration method was carried out using TSI in-house procedure specification with reference to AS TG2 18/v 0.1 and OIML R 111-1.	1.3g
6 kg – 15 kg	Direct measurement via placing the working standard mass on UUT	2.7g
15 kg – 35 kg		60g
1.2 Pressure / Vacuum Gauge <i>0 to +70.0 bar</i>	TS-107 The calibration method was carried out using BS EN 837-1, 837-2 and 837-3 specification, as a guide.	0.0018 % FS
<i>0 to -0.9 bar</i>	Direct measurement of UUT from the Pressure Calibrator	0.015 % FS
1.3 Torque Screwdrivers (0.04 – 0.14) Nm (0.14 – 0.50) Nm (0.50 – 2.00) Nm (2.0 – 13.6) Nm	TS-101B The calibration was carried out using ISO 6789:2017 specifications as a guide. Direct measurement of UUT from the Torque Measurement System.	4.7% - 1.3% of reading 3.5% - 1.5% of reading 1.3% - 0.93% of reading 1.2% - 0.70% of reading
D. DIMENSIONAL		
1.1 Caliper <i>(Vernier / Dial / Digimatic)</i> 0 – 150 mm / 6 inch 0 – 300 mm / 12 inch 0 – 600 mm / 24 inch	TS-103A The calibration method was carried out using JIS B 7507-2016 specification, as a guide. Direct measurement to UUT from Caliper Checker	6.0 µm / 0.0003 inch 6.0 µm / 0.0003 inch 6.0 µm / 0.0003 inch
1.2 Dial Gauge / Indicator <i>0 – 25 mm</i>	TS-104A The calibration method was carried out using JIS B 7503-2017 specification, as a guide. Direct measurement of UUT from Calibrator Tester	0.8 µm



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1.3 Dial Test Gauge / Indicator 0 – 0.05 inch 0 – 0.2 mm 0 – 0.8 mm	TS-105A The calibration method was carried out using JIS B 7533-2015 specification, as a guide. Direct measurement of UUT from Calibrator Tester	0.00006 inch 1.0 μm 1.5 μm
1.4 Micrometer 0 – 25 mm	TS-106B The calibration method was carried out using JIS B 7502-2016 specification, as a guide. Direct measurement of UUT from Gauge Block	0.9 μm

* CMC is expressed as an expanded uncertainty estimated at a level of confidence of approximately 95 %.

Approved signatories :

- Mr Lim Beng Soon - Items A1 to A9, B1 only.
Mr Bernard Chew Lit Min - Items A8 to A10 only
Mr Chin Wei Ming - Items C & D
Mr Andrew Chia Mu En - Items C & D
Mr Randy Gee - A1 – A7 only

Note :

This laboratory is accredited in accordance with the recognised International Standard ISO/IEC 17025. A laboratory's fulfilment of the requirements of ISO/IEC 17025 means the laboratory meets both the technical competence requirements and **management system requirements** that are necessary for it to consistently deliver technically valid calibrations. The **management system requirements** in ISO/IEC 17025 are written in language relevant to laboratory operations and operate generally in accordance with the principles of ISO 9001.